

Search Notes

Application/Control No.

10/801,219

Examiner

Y. J. Han

Applicant(s)/Patent under
Reexamination

MEGAW ET AL.

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
323	312		
	313		
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341	119		
327	539		
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323	318		
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INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR